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| Notice of References Cited | Application/Control No. 10/550,166 | Applicant(s)/Patent Under Reexamination SCHIELE, STEFAN | |
| | Examiner Albert Hilton | Art Unit 1717 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|------------------------|----------------|
| * | A | US-5,364,658 | 11-1994 | Jeppesen, Anders E. H. | 427/209 |
| * | B | US-6,858,261 | 02-2005 | Bar et al. | 427/542 |
| * | C | US-5,888,592 | 03-1999 | Biallas et al. | 427/542 |
| * | D | US-5,236,746 | 08-1993 | Kapp-Schwoerer et al. | 427/508 |
| * | E | US-6,176,927 | 01-2001 | Nussbaumer et al. | 118/317 |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|---------------|----------------|
| | N | DE 19857045 A1 | 06-2000 | Germany | BAER K et al. | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | I | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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